



Email : sales@laboratoryinstrumentindia.com

Product Name :
Scanning Electron Microscope Bench Top

Product Code :
LBNY-0001-830036



Description :

Scanning Electron Microscope Bench Top

Technical Specification :

Combines innovative technological features with an intuitive interface, to deliver adaptability and flexibility in a powerful, automated, lab-friendly package.

Cutting-edge technology and circuitry provides unrivaled imaging performance, even in variable-pressure environments, a feature previously only available in a full-sized SEM.

This SEM runs on clean energy for an economical analytical tool, without compromising performance.

Beam energy 1- 30 kv,

Magnification up to 50 000x,

Resolution 15 nm,

With 3 -stage controls and dual imaging detectors,

Low vacuum capability for non-conductive samples, variable spot size control, optimal x-ray generation for EDS analysis, Backscatter (BSE) and Secondary (SE) detector.

EDS elemental analysis.

Antivibration table.

Provide computer, software, commission and staff training.

Laboratory Instrument India

